

DOCKET NO: 296431US2PCT

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF :
HISAO IGARASHI, ET AL. : EXAMINER: TANG, MINH NHUT
SERIAL NO: 10/593,830 :
FILED: SEPTEMBER 22, 2006 : GROUP ART UNIT: 2829
FOR: PROBE APPARATUS, WAFER :
INSPECTING APPARATUS PROVIDED
WITH THE PROBE APPARATUS AND
WAFER INSPECTING METHOD

AMENDMENT UNDER 37 C.F.R. § 1.111

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Responsive to the Office Action dated February 26, 2008, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Amendments to the Drawings begin on page 8 of this paper and include an attached replacement sheet.

Remarks/Arguments begin on page 9 of this paper.